



Study of radiation tolerance of Cu(In, Ga)Se₂ detector

K. Itabashi¹, T. Ishobe², M. Miyahara¹, J. Nishinaga³,
H. Okumura⁴, M. Togawa¹

KEK¹, REKEN², AIST³, Univ. of Tsukuba⁴

Contents

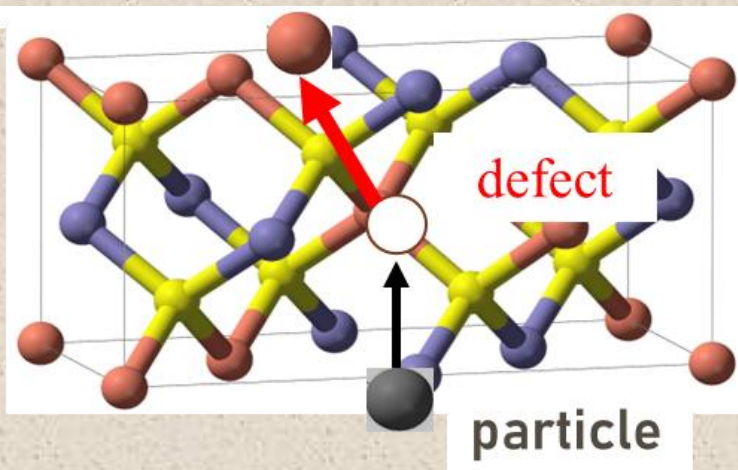
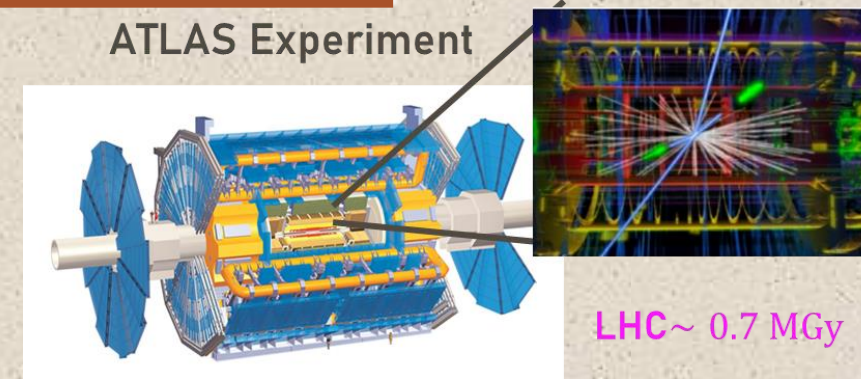
- Introduction
- Study of radiation tolerance of CIGS
 - Heavy ion ($^{132}\text{Xe}^{54+}$) irradiation experiment
 - Proton irradiation experiment

Study of the radiation tolerant semiconductors

Hadron Collider Experiment

High energy experiment (LHC) plans to construct the higher energy and luminosity accelerator for the new particle search.

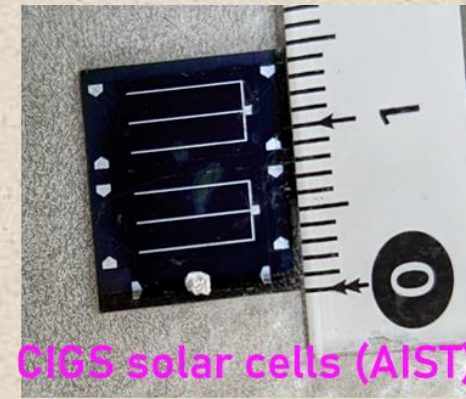
→ Giving serious radiation damage to detectors.



Performance deterioration by radiation damage

- Increasing leakage current
- Increasing depletion voltage
- Decreasing in collected charge from signal

Radiation hardness semiconductor (CIGS)

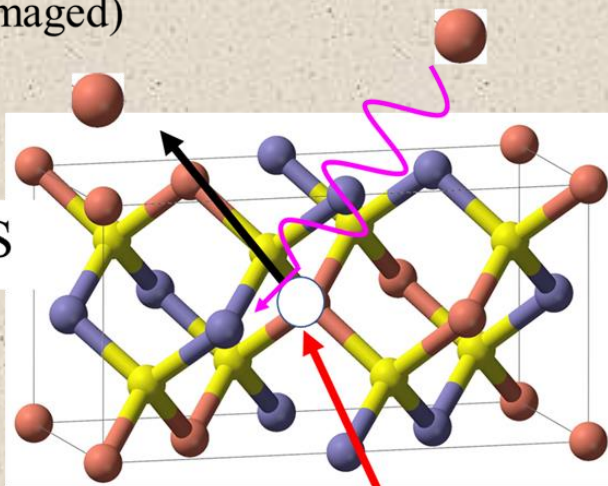


CIGS solar cells (AIST)

A CIGS is an alloy semiconductor of CuInSe_2 and CuGaSe_2

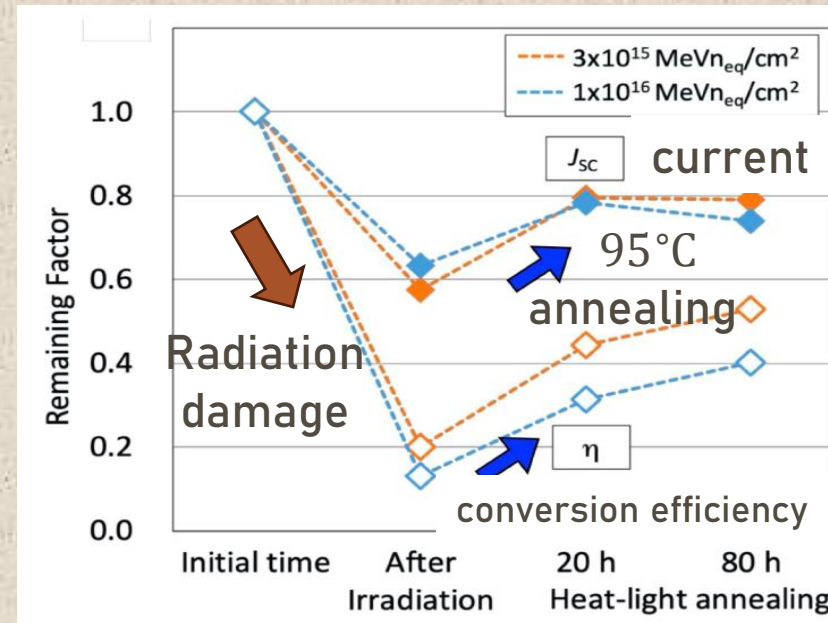
- Developed as a solar cells
- **High radiation tolerance (recovered radiation damage by heat annealing)**

Knocked out (damaged) Restored (recovered)



CIGS

Radiation
(proton, neutron etc.)



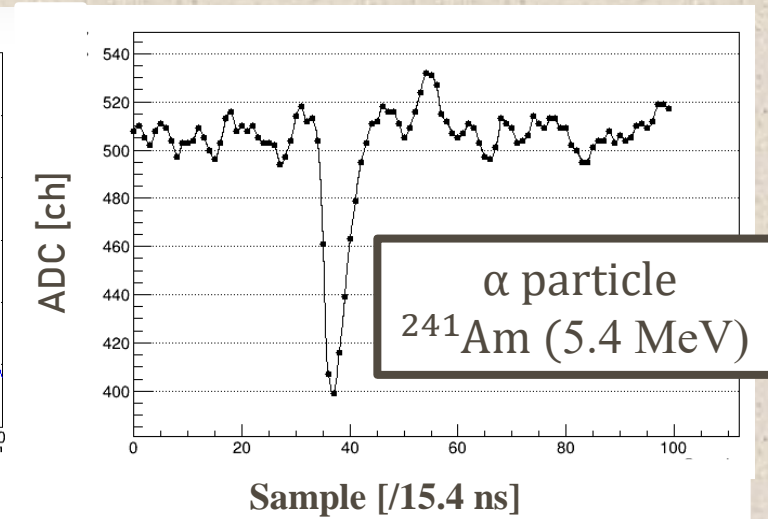
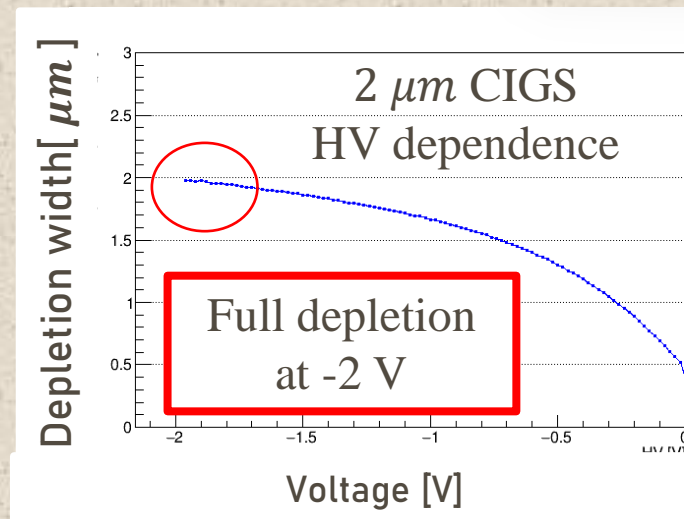
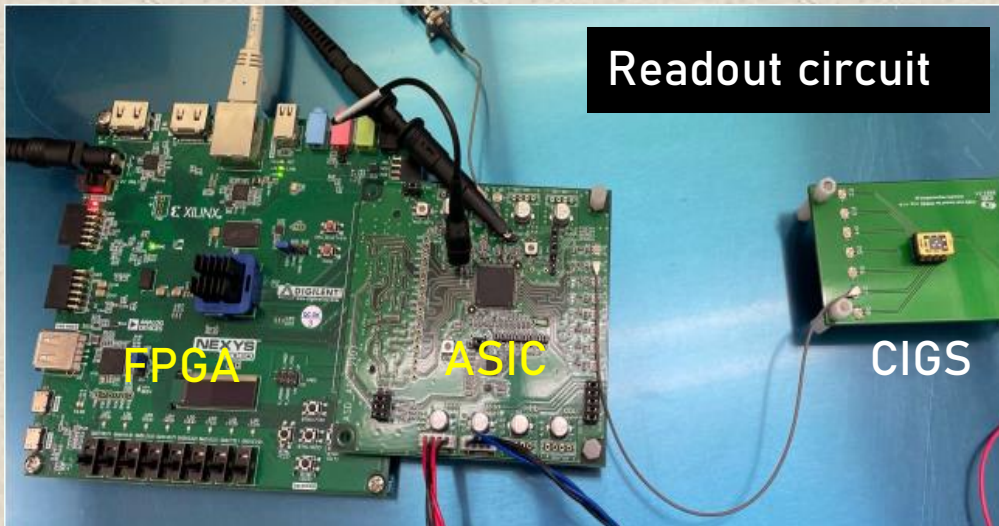
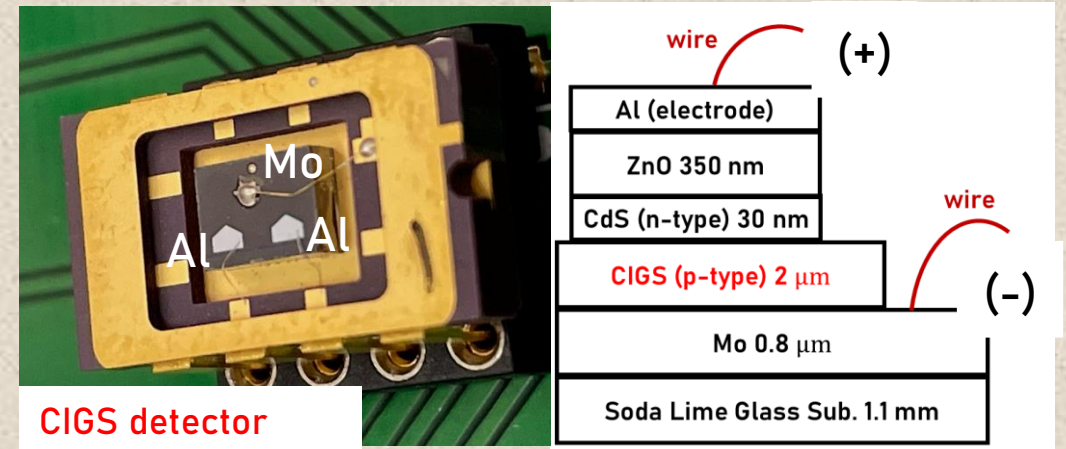
Observed current recovery by thermal annealing (in CIGS solar cells)

Challenging in development of CIGS detector radiation hardness detector with CIGS

Development of CIGS detector

Specifications of CIGS detectors

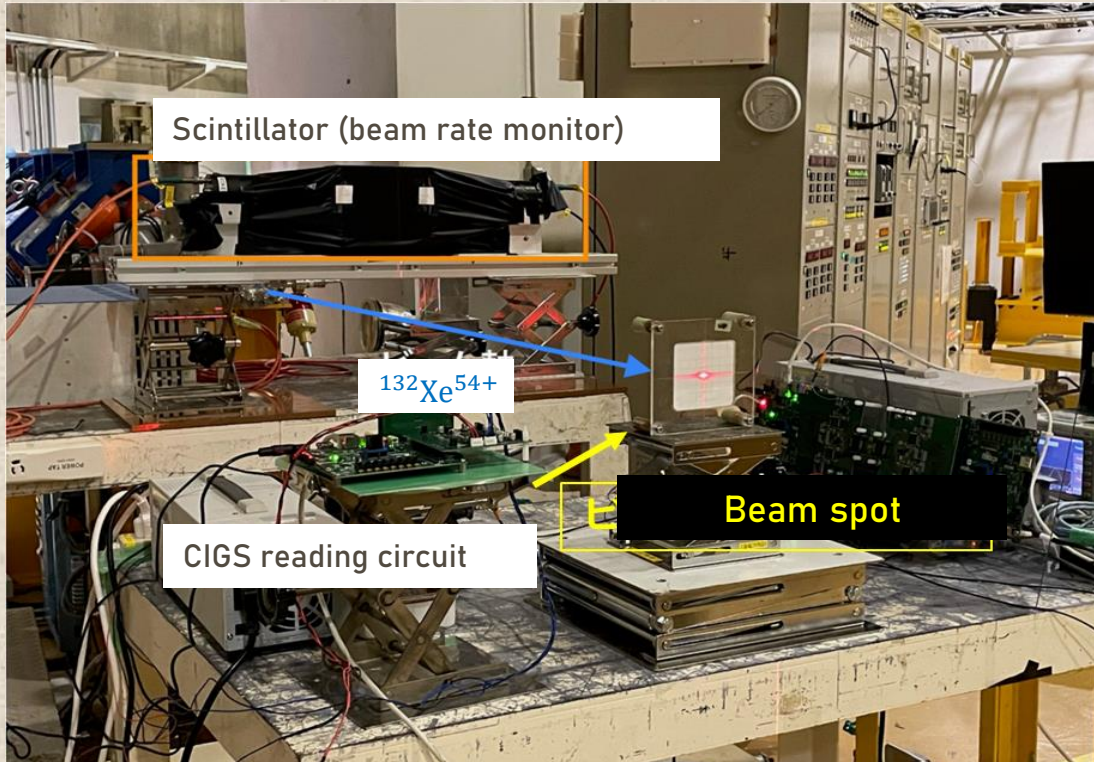
- p-type (CIGS), n-type (CdS)
- thickness $2\ \mu\text{m}$, $5\ \mu\text{m}$ ($10\ \mu\text{m}$ developing)
- Active area : $5\ \text{mm}^2/\text{channel}$
- Operation Voltage : $-2\ \text{V}$



Contents

- Introduction
- **Study of radiation tolerance of CIGS**
 - **Heavy ion ($^{132}\text{Xe}^{54+}$) irradiation experiment**
 - Proton irradiation experiment

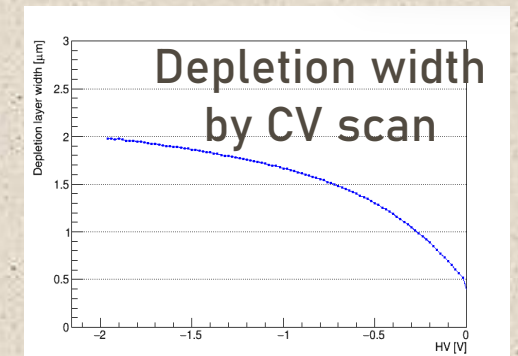
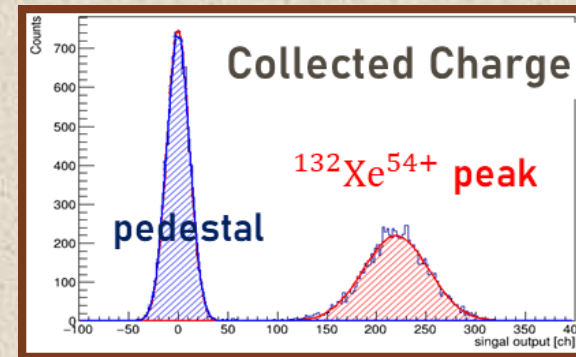
Irradiation experiment at HIMAC



HIMAC Beam Condition

- Beam : $^{132}\text{Xe}^{54+}$ ion
- Energy : 400 (MeV/u)
- Beam size (ϕ) : 3-5 mm
- Fluence : 10^7 /3.3 s (ppp)

Measurement parameters

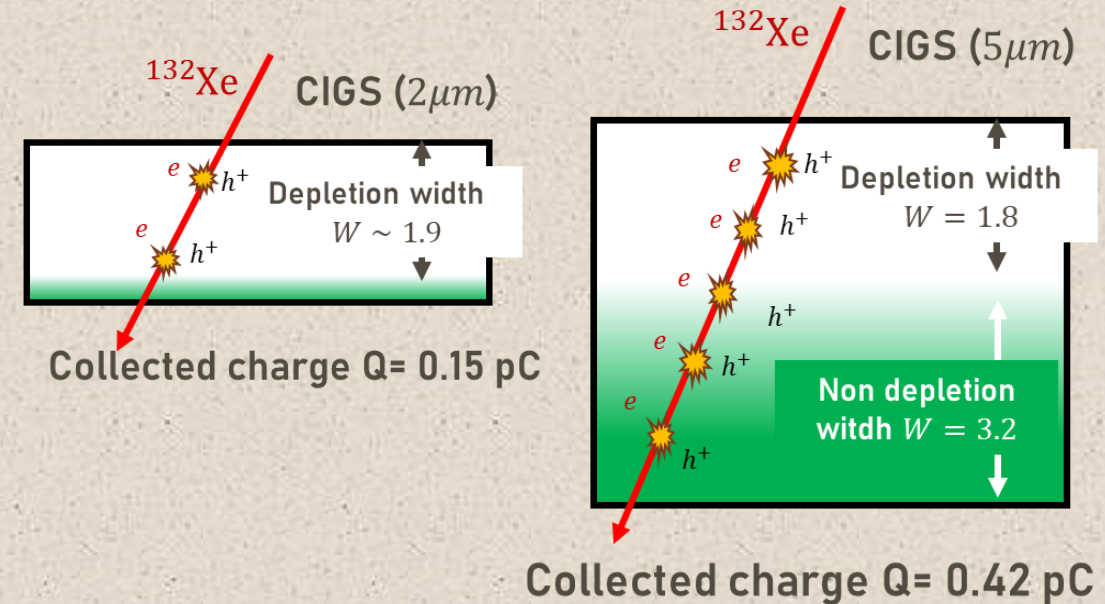
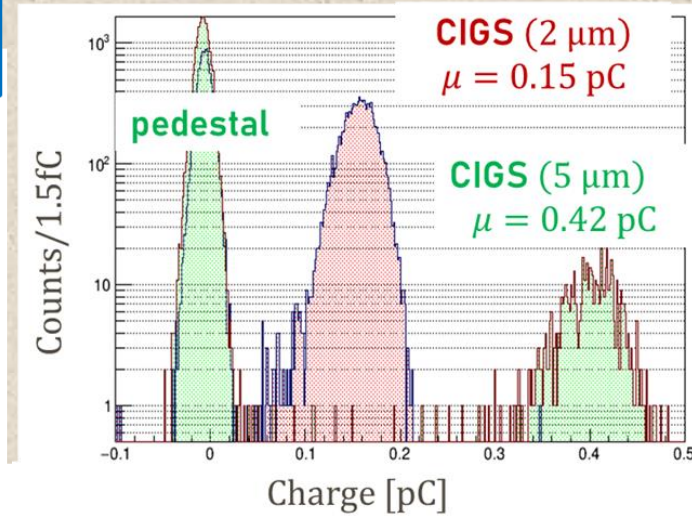
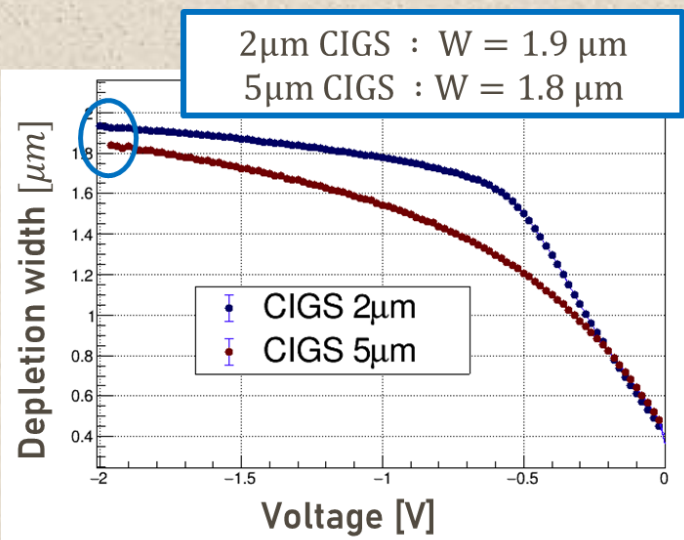


1. CIGS thickness dependence (2 μm and 5 μm thick CIGS detectors)
2. Recovery mechanism of radiation damage (2 μm thick CIGS detector)

Thickness dependence of CIGS detector performances

The collected charge is proportional to depletion width ($Q \propto W$).

Both of depletion width ($V=-2V$) are about $2 \mu\text{m}$, but collected charge of $5 \mu\text{m}$ CIGS detector was **2.5 times larger** than one of $2 \mu\text{m}$ CIGS detector



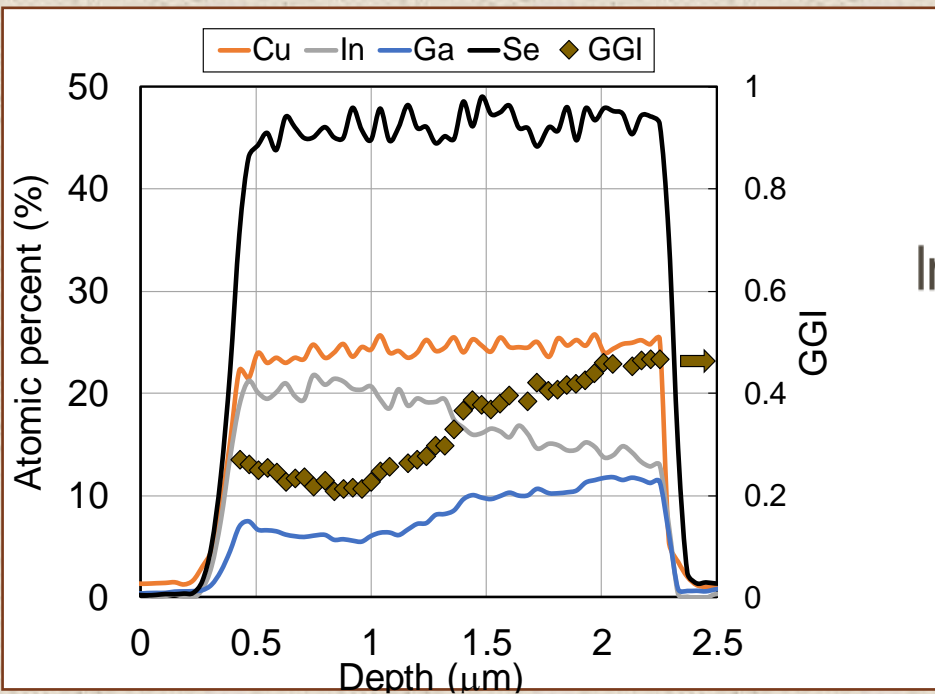
Is it possible to collect charges in non-depletion region ??

Energy gradient of CIGS layer

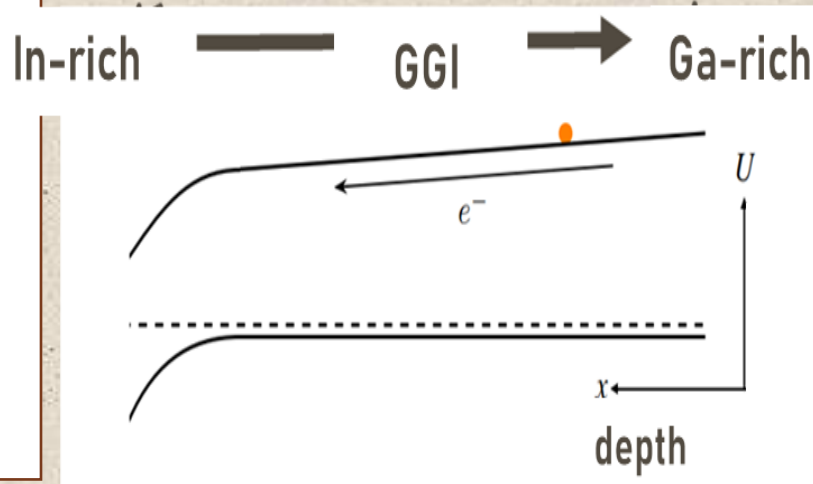
CIGS is an alloy semiconductor CuInSe_2 and CuGaSe_2 .

Energy gap of CIGS changes with Ga composition ratio ($\text{GGI} = [\text{Ga}] / ([\text{In}] + [\text{Ga}])$).

$$1.01 \text{ eV [GGI = 0]} < E_g < 1.64 \text{ eV [GGI = 1]}$$



CIGS layer has GGI gradient for depth direction
→ Promoting electron diffusion

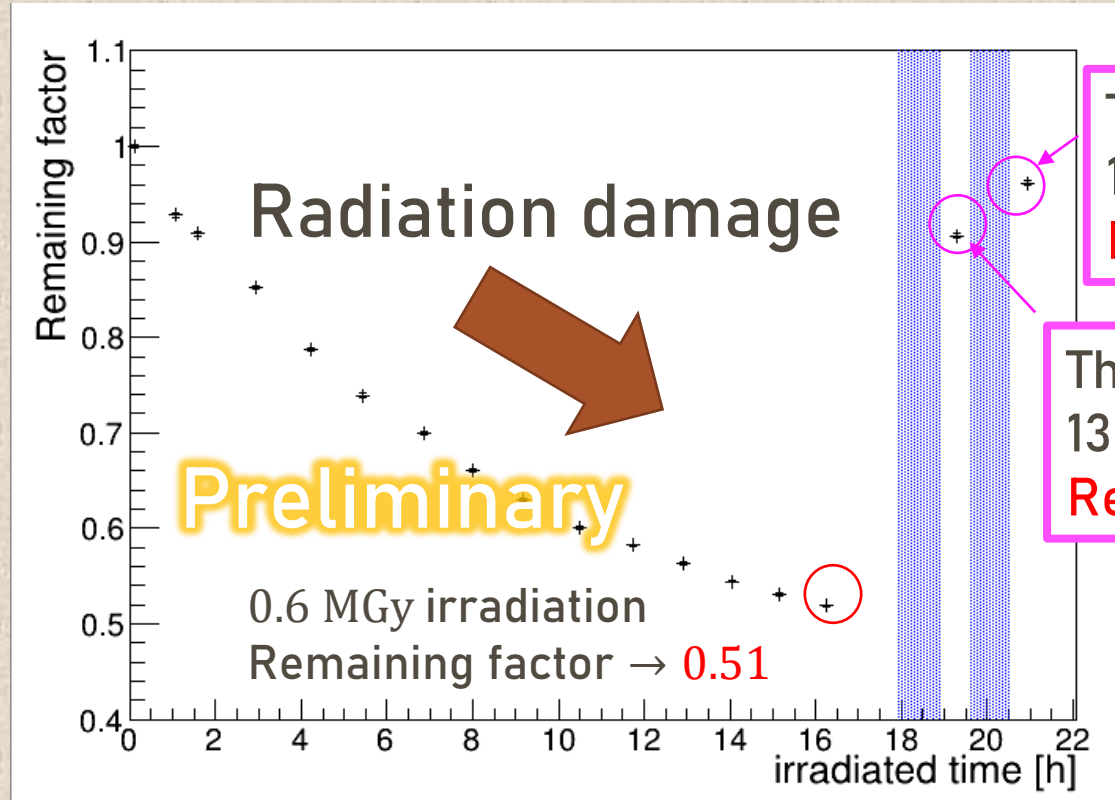
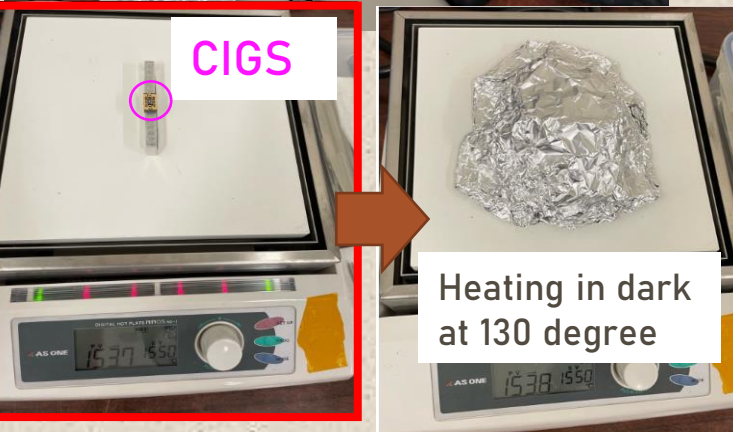
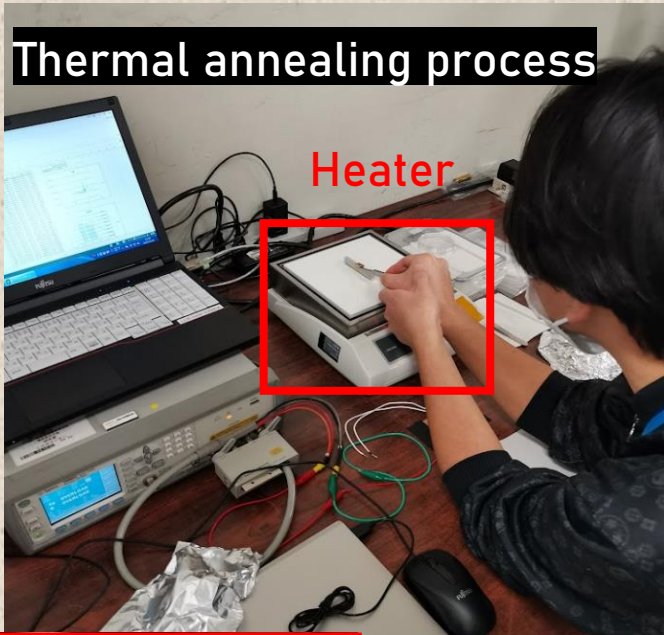


Not need for full depletion



It allows low voltage operation!

Study of the recovery mechanism by thermal annealing

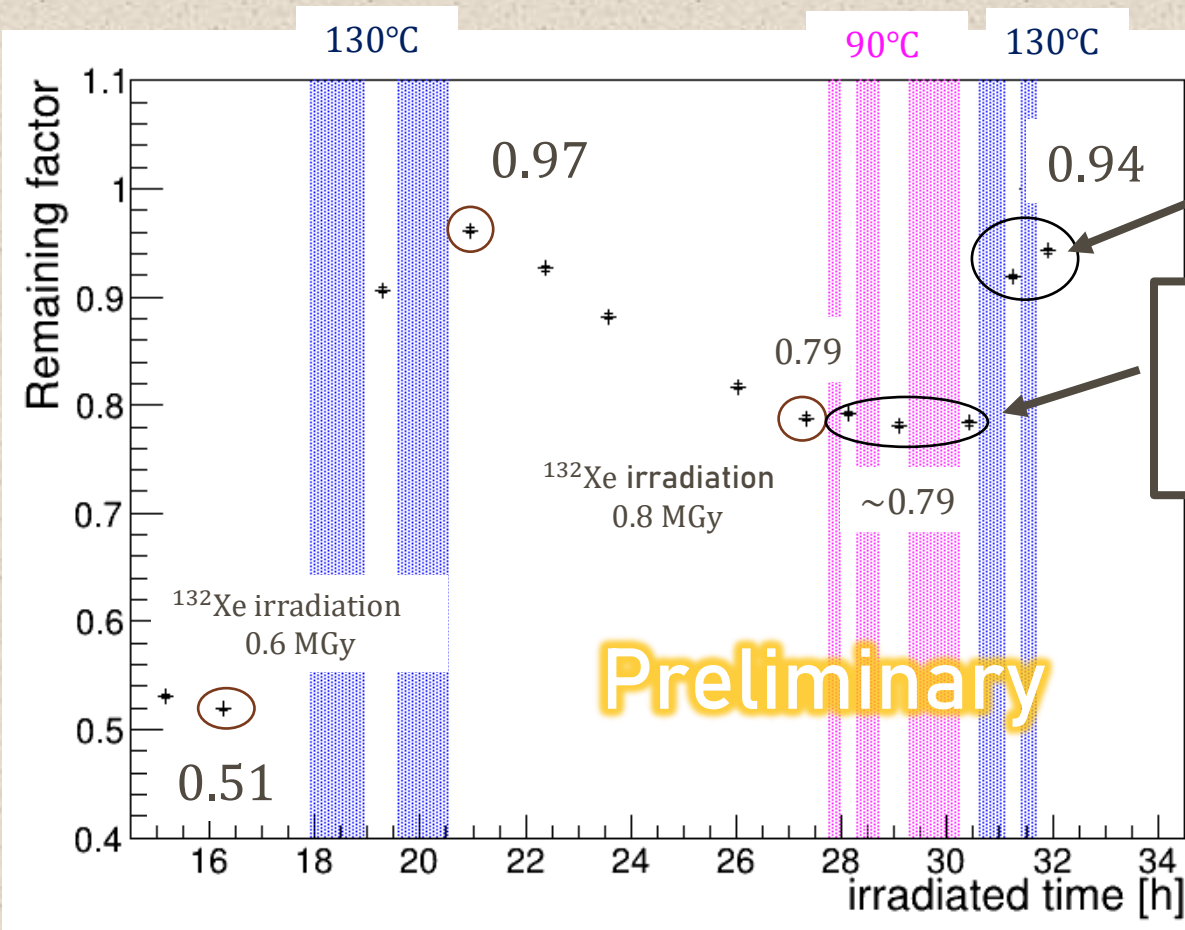


Thermal annealing
130°C (2h)
Remaining factor 0.96

Thermal annealing
130 °C (1h)
Remaining factor 0.92

After 2 hours thermal annealing at 130 °C
Recovered to the same level as before irradiation

Study of the recovery system by thermal annealing (2)

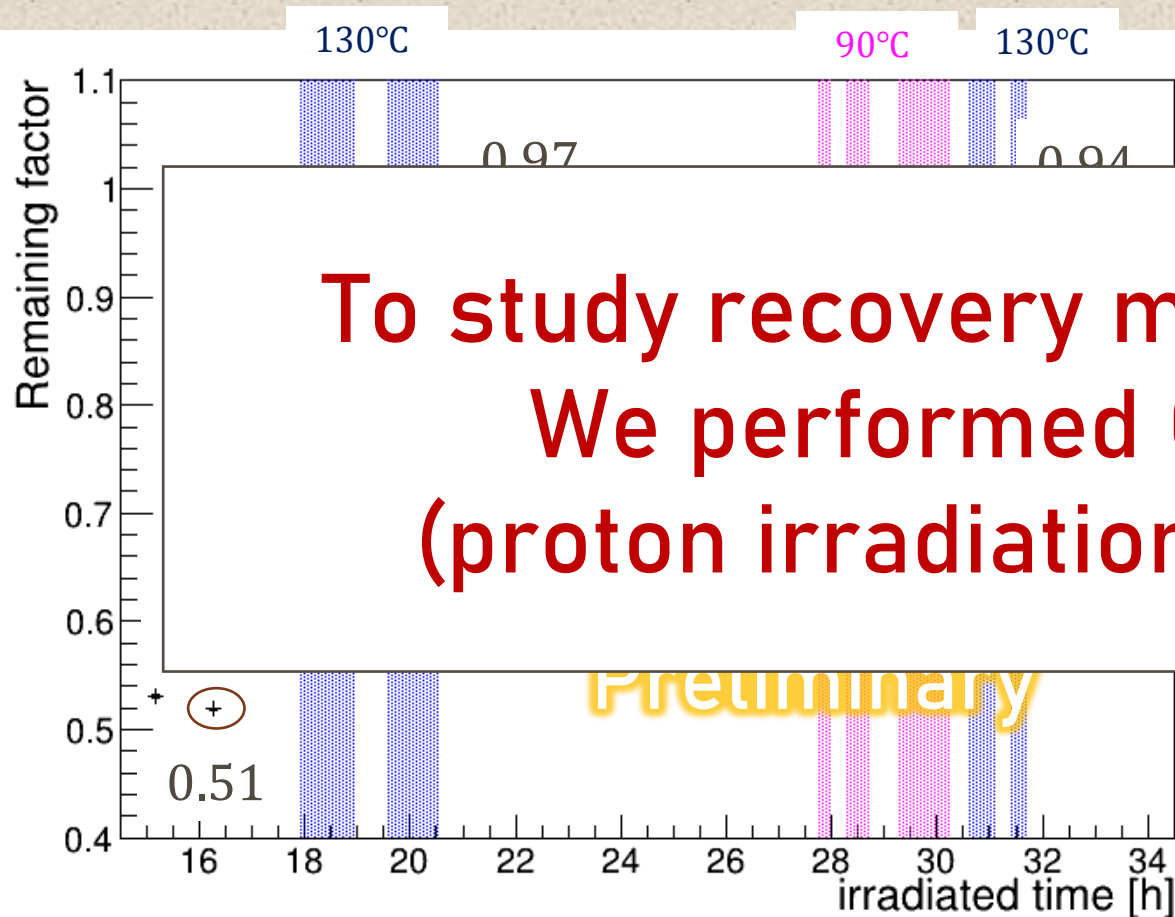


2nd 130°C thermal annealing
(+30 min, +20 min)
0.79 → **0.94 (+50 min)**

90°C thermal annealing
(+15 min, +30 min, +1h)
Not sufficient recovery (insufficient annealing time)

- Thermal annealing mechanism has
- **Strong temperature dependence**
 - **Continuity of thermal recovery**

Study of the recovery system by thermal annealing (2)



2nd 130°C thermal annealing
(+30 min, +20 min)

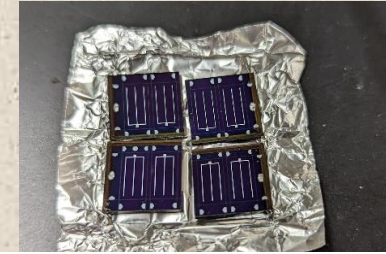
To study recovery mechanism more detail,
We performed CYRIC experiment
(proton irradiation to CIGS solar cells)

- Strong temperature dependence
- Continuity of thermal recovery

Contents

- Introduction
- **Study of radiation tolerance of CIGS**
 - Heavy ion ($^{132}\text{Xe}^{54+}$) irradiation experiment
 - **Proton irradiation experiment**

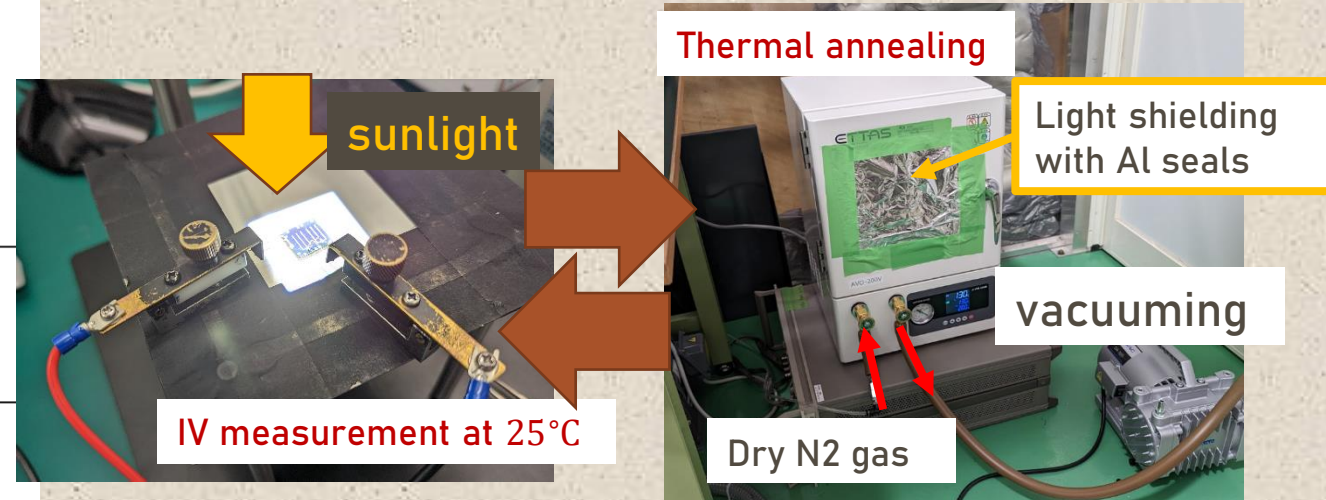
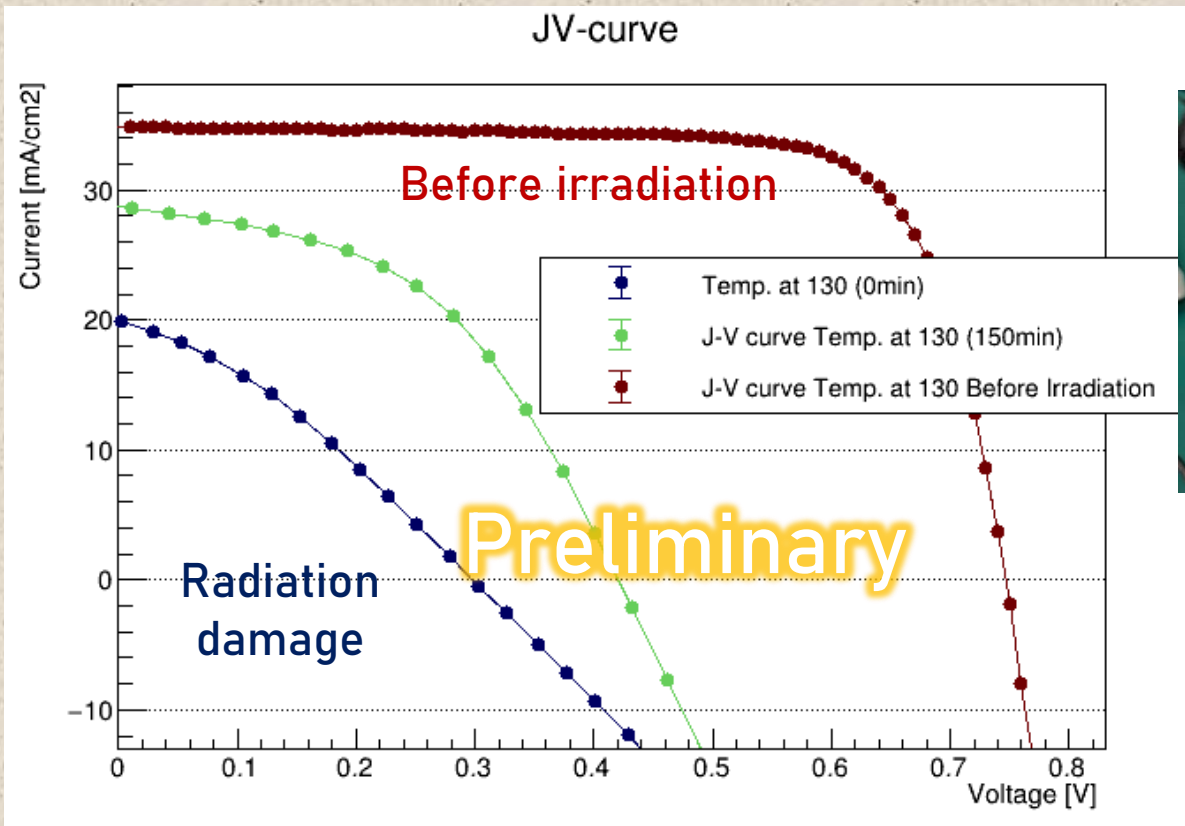
Proton irradiation experiment at CYRIC



CIGS solar cells (AIST)

CYRIC experiment : Irradiated 70 MeV proton to CIGS solar cells ($7 \times 10^{15} \text{ n}_{\text{eq}}$)

→ Study the heating **time** and **temperature** dependences of recovery mechanism



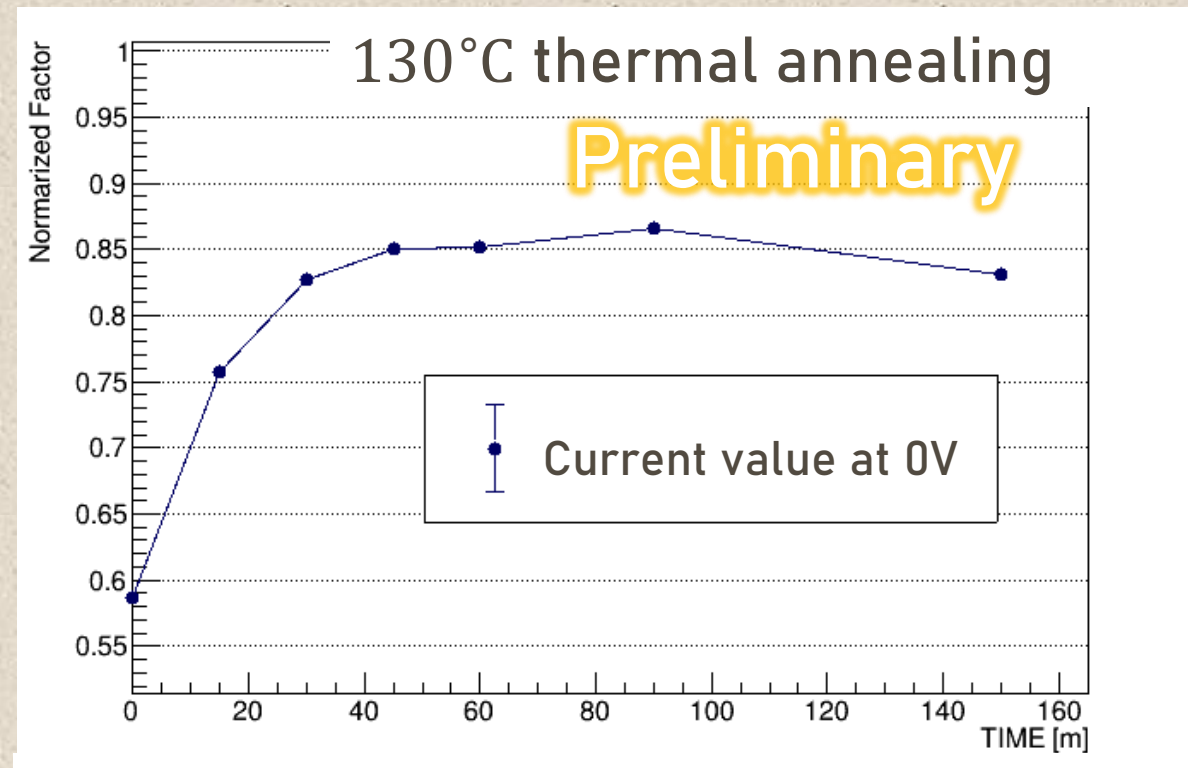
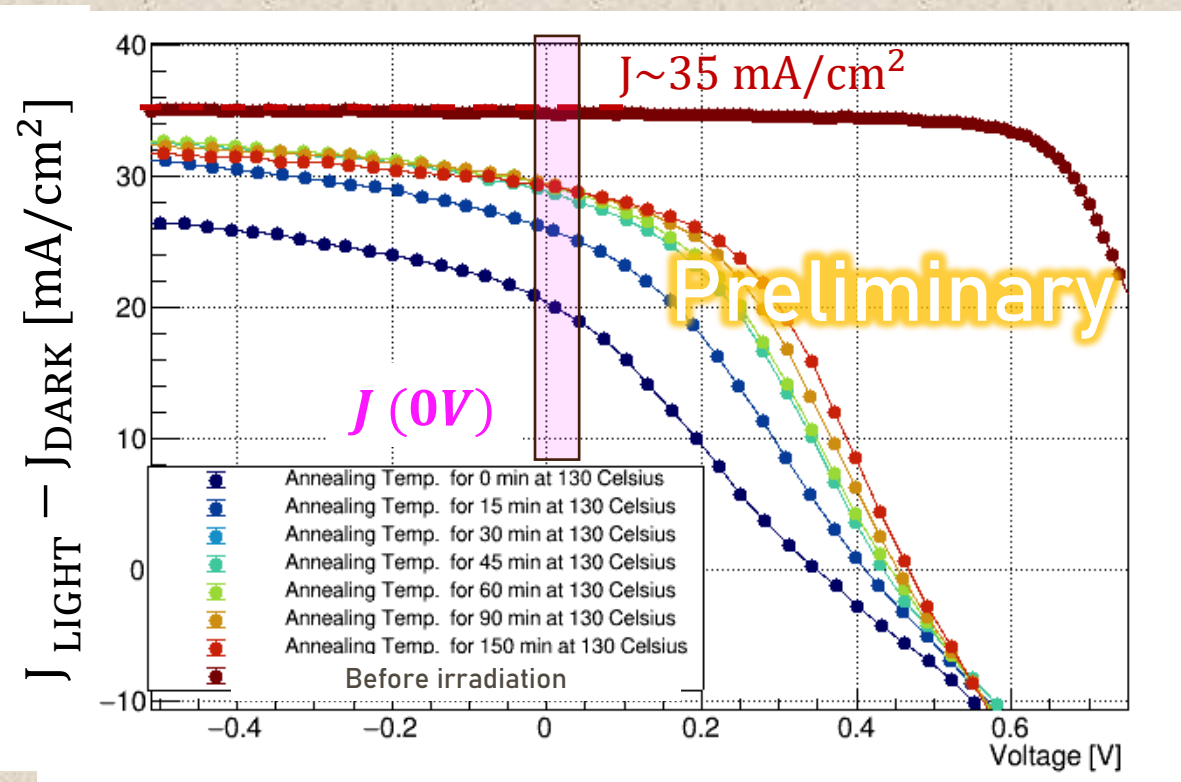
IV curve of CIGS solar cells

- J [mA/cm²] decreased due to proton irradiation
 $J_{\text{SC}}(0\text{V}) : 35 \rightarrow 20 \text{ mA/cm}^2$
- Recovered J by thermal annealing (2.5 h) at 130°C
 $J_{\text{SC}}(0\text{V}) : 20 \rightarrow 28 \text{ mA/cm}^2$

Current recovery dependence of annealing time

The measurement current with incident sunlight is including dark current.

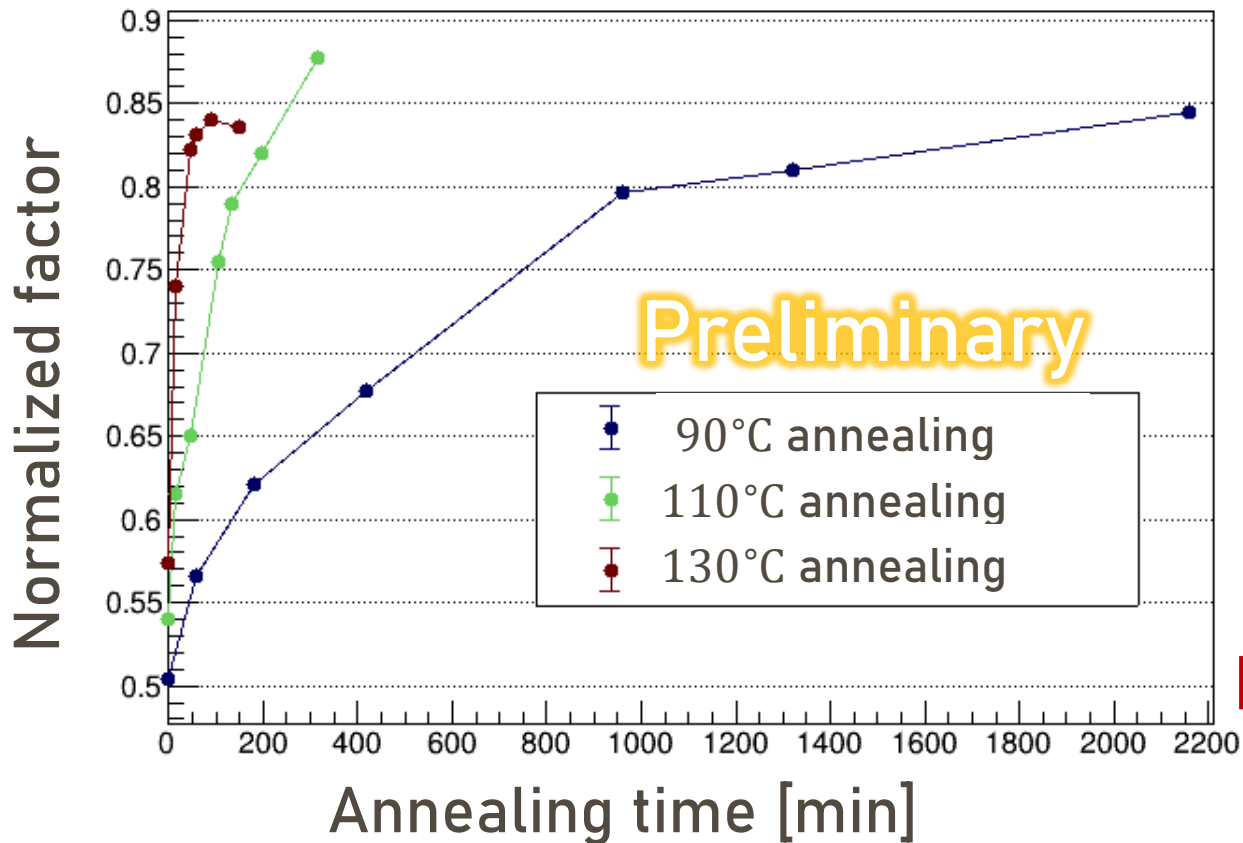
$$\text{Excluded dark current : } J = J_{\text{LIGHT}} - J_{\text{DARK}}$$



J recovered rapidly to saturation value ($\sim 1h$)

Heating temperature dependence of recovery speed

I annealed CIGS solar cells at three differential temperatures (90°C, 110°C, 130°C).



130°C annealing : $J_{0V} = 0.57 \rightarrow 0.85$ (1h)

90°C annealing : $J_{0V} = 0.50 \rightarrow 0.57$ (1h)

Comparable with recovery speed of collected charge at HIMAC experiment

130°C annealing: $Q = 0.79 \rightarrow 0.94$ (1h)

90°C annealing: $Q = 0.79 \rightarrow 0.79$ (1h)

Recovery speed is greatly depending on heating temperature

Conclusion

- **CIGS semiconductor has been developed as a solar cells.**
 - Observed recovery of radiation damage by thermal annealing
 - We developed pixel type of CIGS detector ($2\ \mu\text{m}$)
- **Heavy ion irradiation experiment at HIMAC**
 - Observed recovery of collected charge and leakage current by 130°C annealing (→ same level of before irradiation)
- **Proton irradiation experiment at CYRIC**
 - Observed strong annealing temperature dependence of recovery speed
→ Comparable with recovery speed of HIMAC experiment

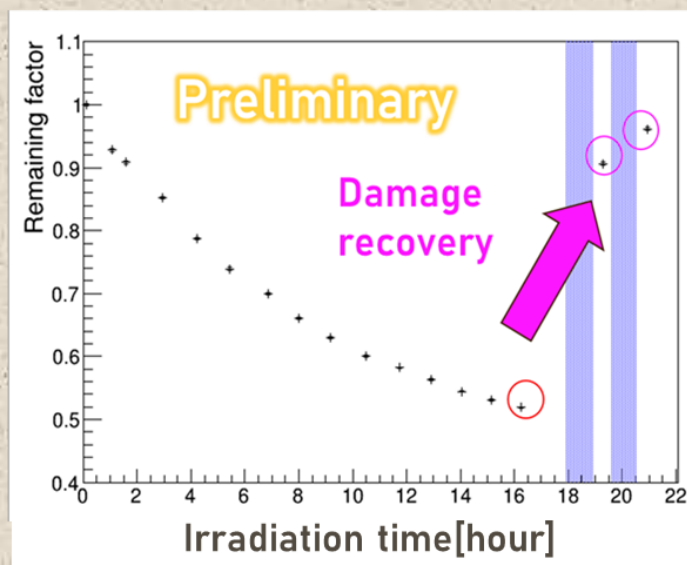
Thank you

Backup

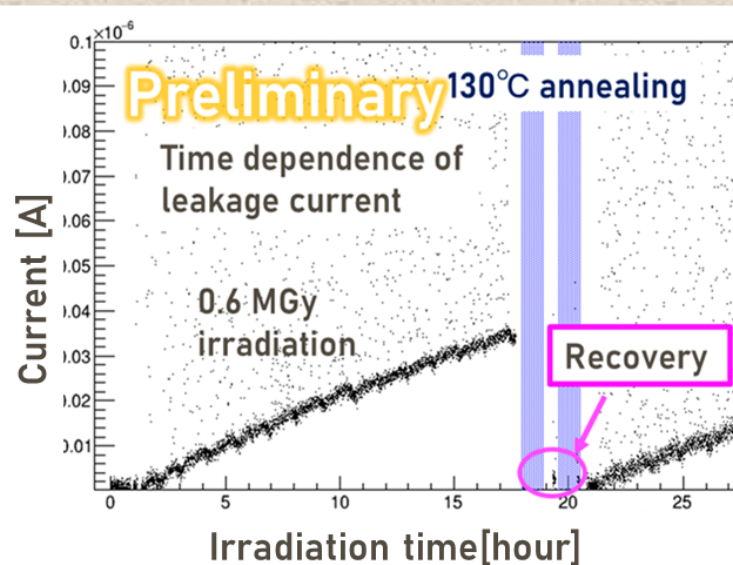
Results of heat treatment at 130°C in each parameter

Annealing results of three detector performances

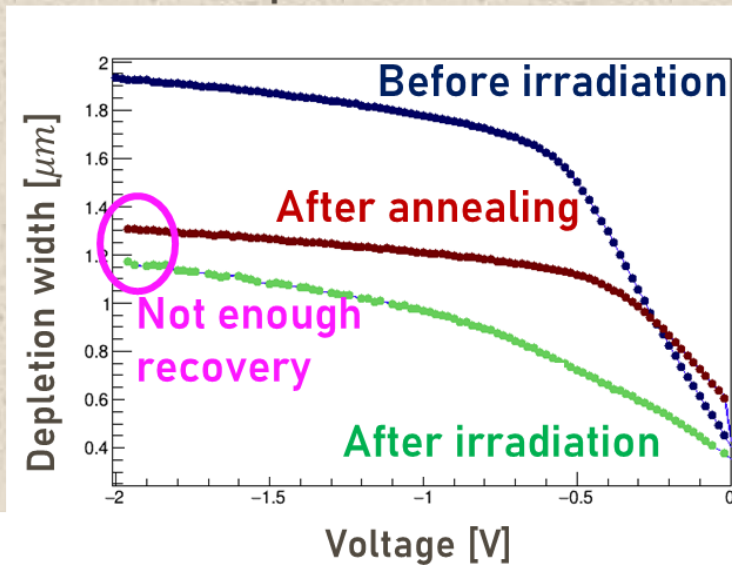
1. Collected charge from Xe beam



2. Leakage current



3. Depletion width

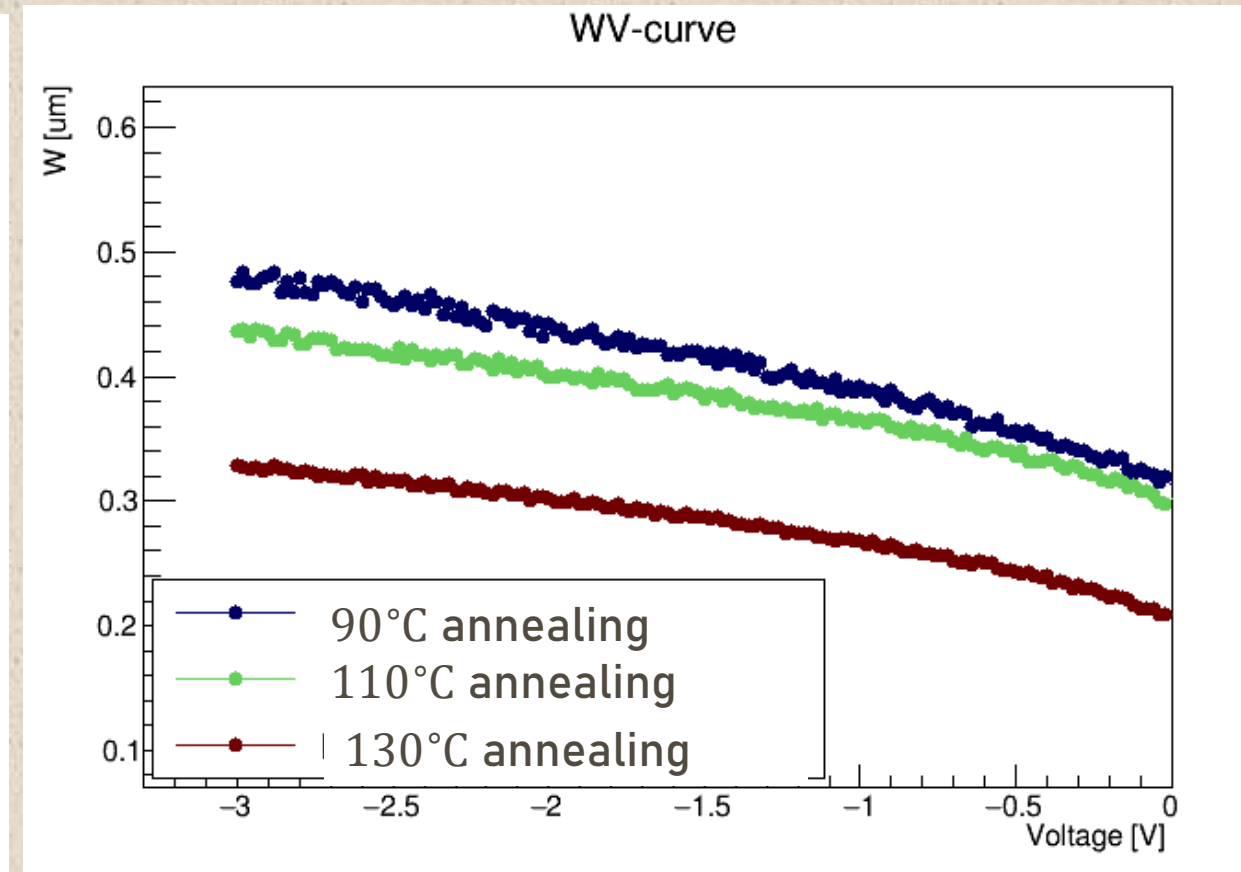
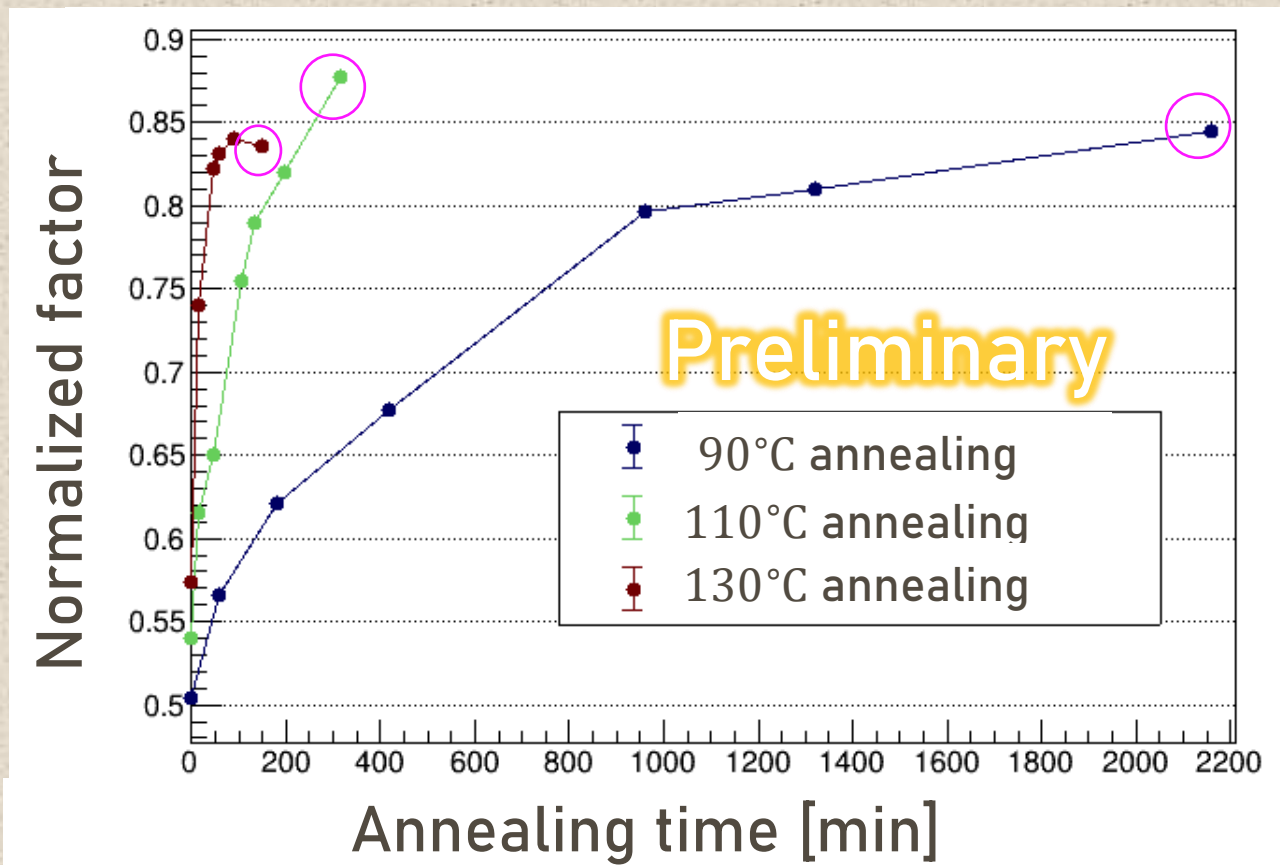


By 130°C thermal annealing for few hours

Recovered collected charge and leakage current → decreasing lattice defects

Not recovered depletion width → Not decreasing Ion (acceptor) concentration

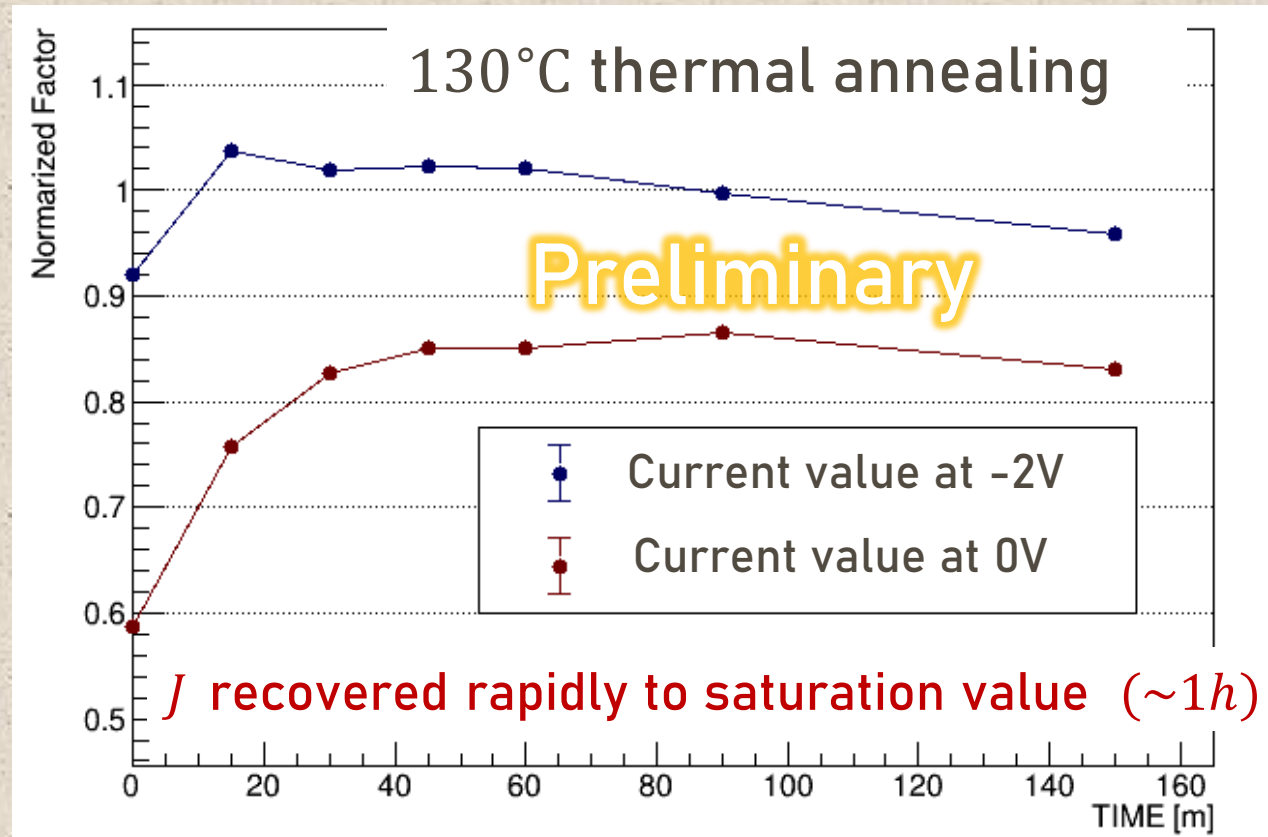
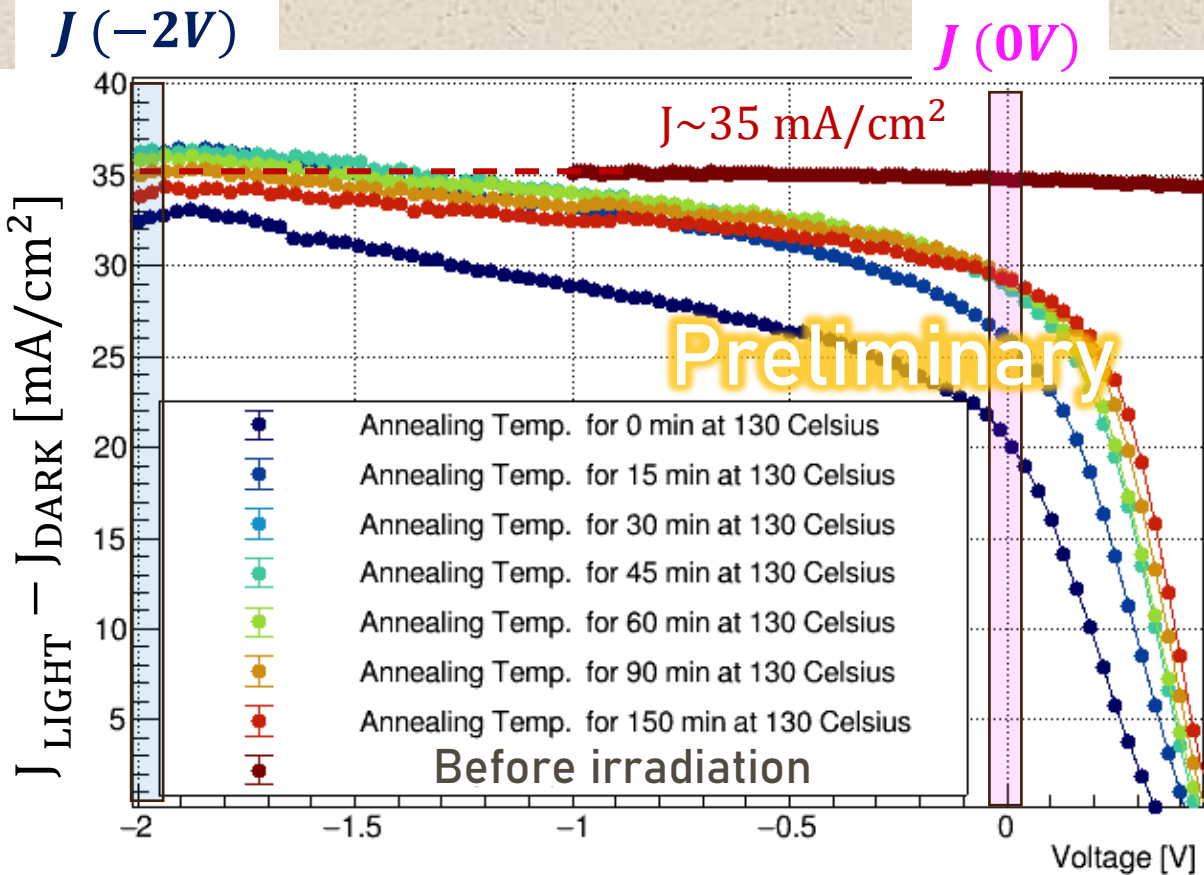
Depletion width at each annealing time



Current recovery dependence of annealing time

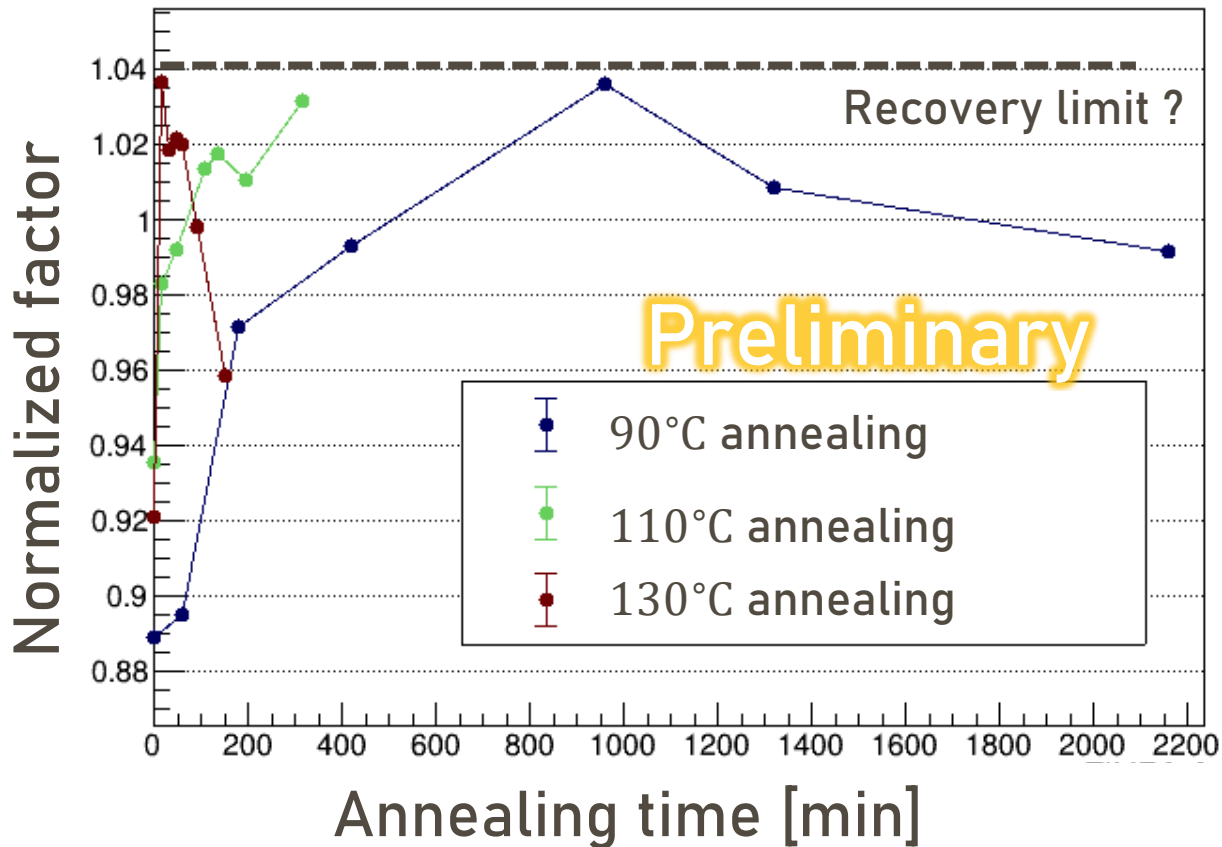
The measurement current with incident sunlight is including dark current.

$$\text{Excluded dark current : } J = J_{\text{LIGHT}} - J_{\text{DARK}}$$



Heating temperature dependence of recovery speed

I annealed CIGS solar cells at three differential temperatures (90°C, 110°C, 130°C).



130°C annealing : $J_{2V} = 0.92 \rightarrow 1.04$ (1h)

90°C annealing : $J_{2V} = 0.89 \rightarrow 0.895$ (1h)

Comparable with recovery speed of HIMAC experiment

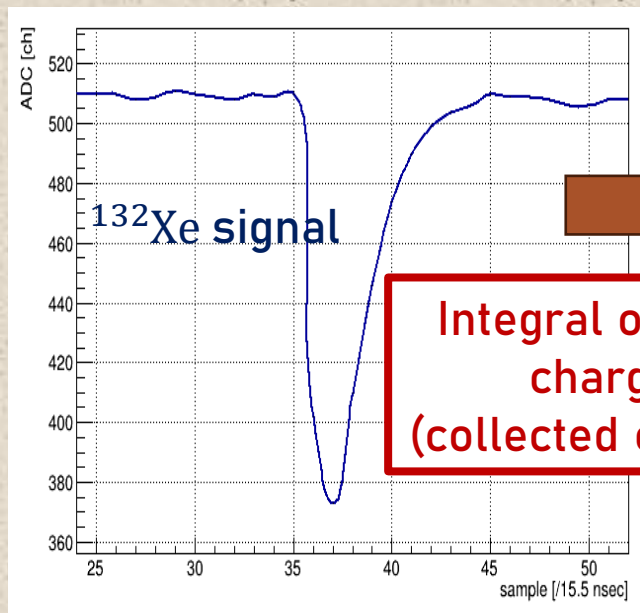
130°C annealing: $Q = 0.79 \rightarrow 0.94$ (1h)

90°C annealing: $Q = 0.79 \rightarrow 0.79$ (1h)

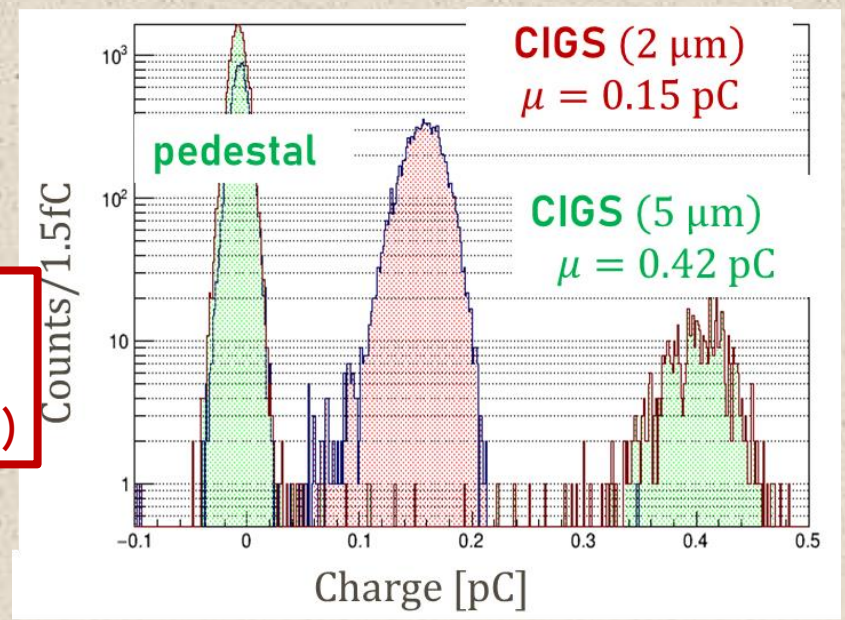
Recovery time is greatly depending on heating temperature

1. Study of Thickness dependence of CIGS (Collected Charge from xenon signal)

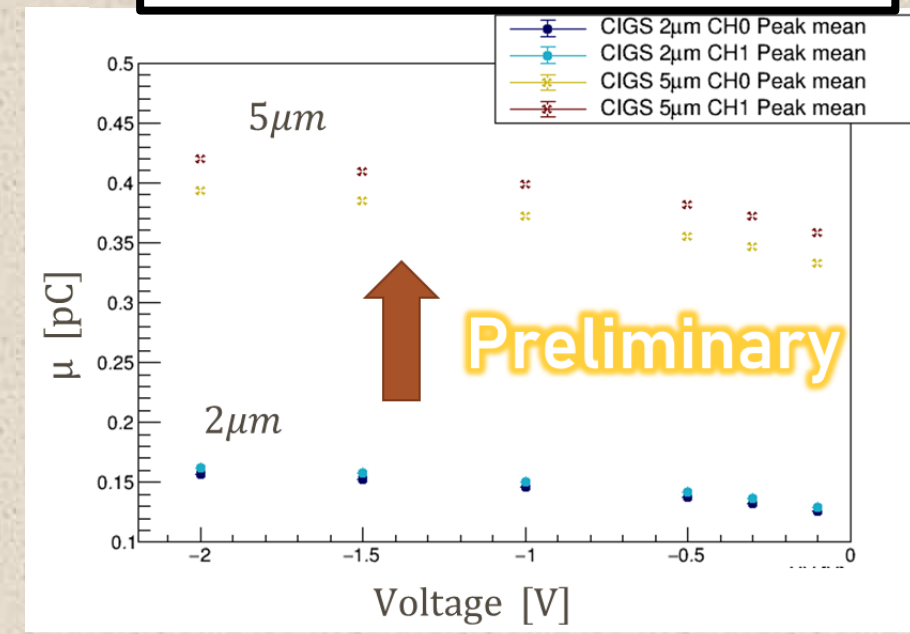
Collected charge evaluation: Xe beams ($p=400$ MeV/u) were irradiated to $2\ \mu\text{m}$ and $5\ \mu\text{m}$ CIGS semiconductor detectors, respectively.



Integral of total charge (collected charge)



$Q_{5\mu\text{m}} \cong 2.5 Q_{2\mu\text{m}}$
(Equivalent to thickness ratio)

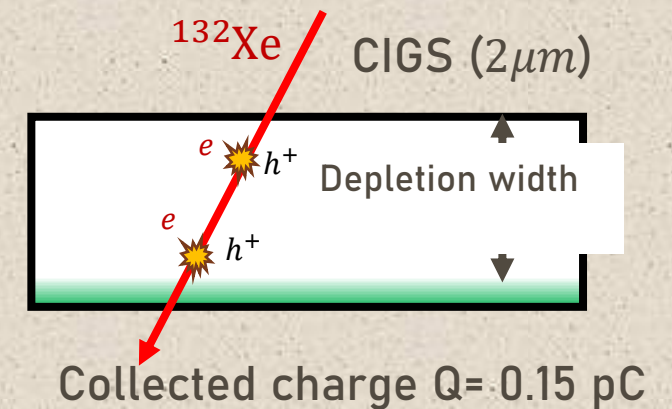
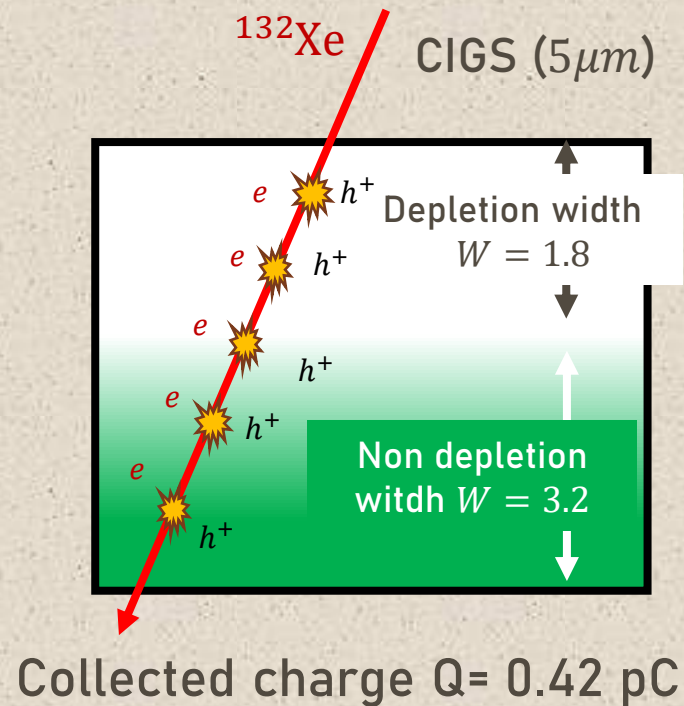
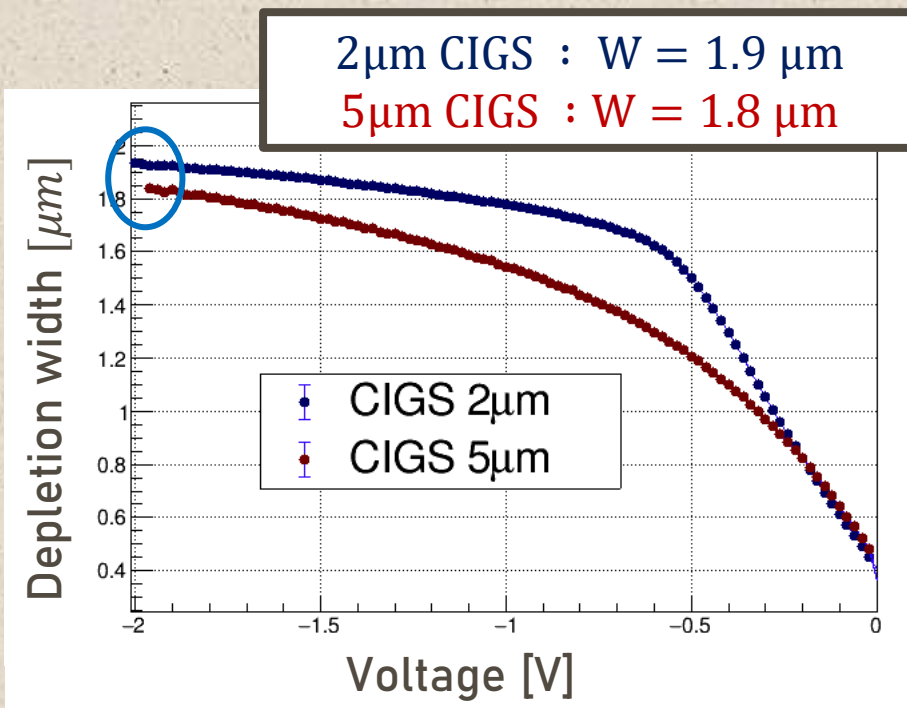


1. Study of Thickness dependence of CIGS (depletion width measurement)

Amount of charge collected is proportional to depletion layer thickness $Q_{\text{det}} \propto W$

Depletion width (W) can be obtained by capacitance (C_j) measurement

$$C_j \equiv dQ/dV = dQ/(WdQ/\epsilon_s) = \epsilon_s/W \quad [W : \text{depletion width, } \epsilon_s : \text{permittivity } (= 13.5\epsilon_0)]$$



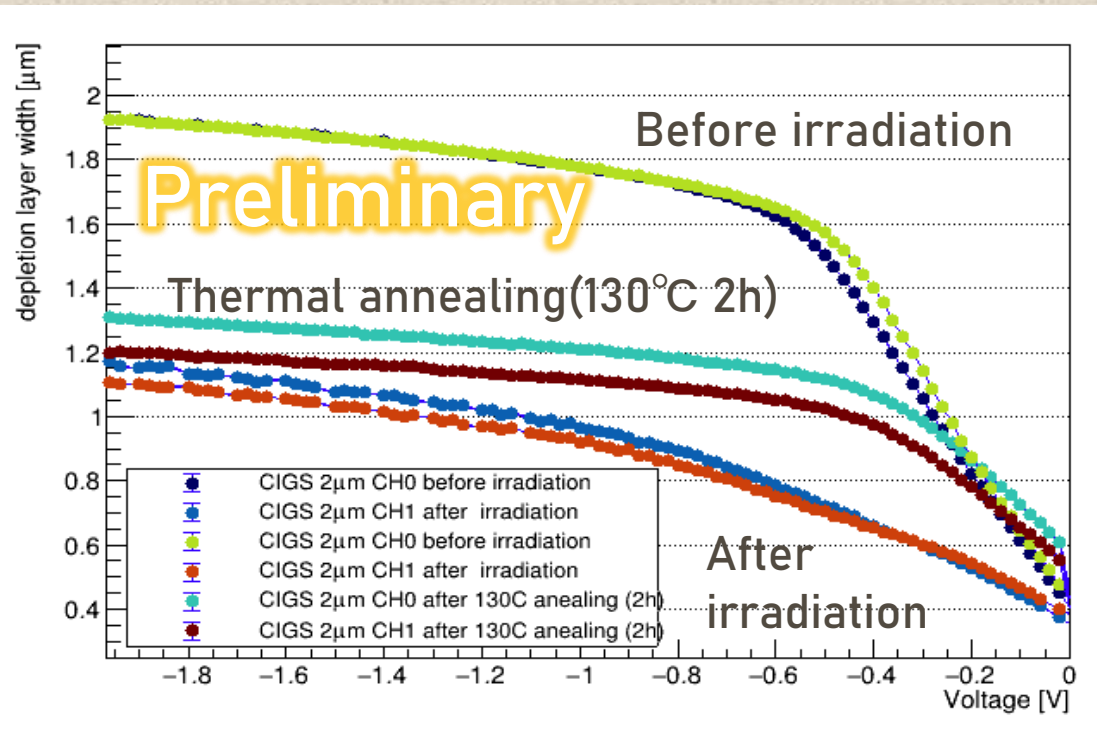
Why can 5 μm CIGS detector collect charge in non-depletion layer ??

Evaluation of depletion layer width after irradiation and thermal annealing

The depletion layer width can be obtained by capacitance measurement

$$C_j \equiv dQ/dV = dQ/(WdQ/\epsilon_s) = \epsilon_s/W$$

[W : depletion width, ϵ_s : permittivity ($= 13.5\epsilon_0$)]



	CH	Before irradiation	After irradiation (0.8 MGy)	After annealing 130°C, 2h
Depletion width [um] at V=-2V	CH0	1.93 (1)	1.17 (0.61)	1.31 (0.68)
	CH1	1.93 (1)	1.11 (0.57)	1.20(0.62)

After irradiation : comparable with decreasing ratio of collected charge ~ 0.6

After annealing : **Not sufficient of recovering**